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2012 30th IEEE VLSI Test Symposium

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Moderator: S. Venkataraman – Intel

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Organizer: I. POLIAN - U. of Passau, H. STRATIGOPOULOS - TIMA

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Organizer: C. THIBEAULT - Ecole de technologie superieure

Panelists:

- H. MANHAEVE - Q-Qtar
- A. SINGH - Auburn U.
- C. THIBEAULT - ETS